



A LIMITED LIABILITY COMPANY

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KLA 6220 WAFER INSPECTION SYSTEM

Vintage 1995
Simple, easy to use and maintain design
Configurable for 2" - 8" wafers
0.09 μ defect sensitivity @ 80% capture
50 μ spatial resolution
0.02 ppm haze sensitivity
0.002 ppm haze resolution
Accuracy within 1%
Windows-based interface
OEM system manuals



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All tools should be inspected and audited by buyers prior to purchase. All items are sold As-Is, Where-Is unless specified.

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